

Frequent problem: Decision making based on statistical information

Examples:

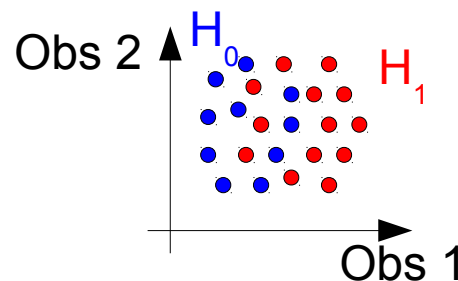
a) Distinguishing different particle species in detector, e. g.  $e - \pi$  separation

Different signals in detector material :

Observables

- specific energy loss in tracking detector
- $E_{\text{ECAL}} / E_{\text{HCAL}}$  ratio
- shower shapes in calorimeter
- ...

P.d.f.s of observables are often different for different hypotheses but they overlap. In this case, the aim is: large efficiency, small background



b) Search for new particles

statistical separation of similar events: background and new particles (signal)

Concepts

Problem: How well do observed data agree with predicted probabilities (hypotheses)?

The hypothesis under consideration is traditionally called null hypothesis  $H_0$ . Often comparison with alternative hypotheses  $H_1, H_2, \dots$

n measured values  $\vec{x} = (x_1, \dots, x_n)$

Each hypothesis characterised through p.d.f.  $f(\vec{x}|H_0), f(\vec{x}|H_1), f(\vec{x}|H_2), \dots$

$(x_1, \dots, x_n)$  could be :

- n measurements of the same random variable (n "events")
- n different observables of an event (E, p, ...)
- Combination of both
- Same measurement from n different experiments

To test agreement between data and given hypothesis, one constructs a function

$$\vec{t}(\vec{x}) \quad \vec{t} = (t_1, \dots, t_m)$$

of  $(x_1, \dots, x_n)$  called test statistic (usually  $t(\vec{x})$  is scalar function)

For each of the hypotheses, there is a p.d.f. for the statistic  $t$ :  $g(t|H_0)$ ,  $g(t|H_1)$ , etc

Decision to accept or reject hypothesis  $H_0$  by defining:

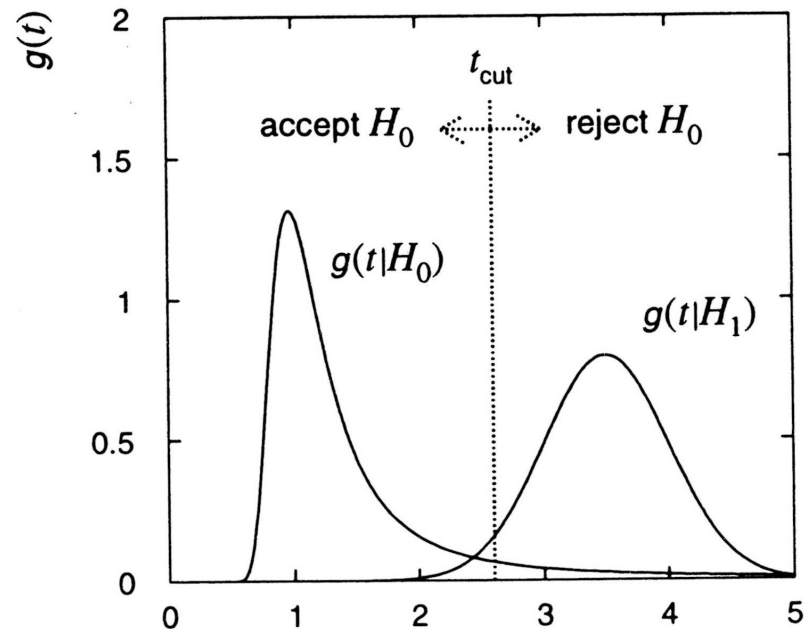
critical region (reject  $H_0$ )

acceptance region (accept  $H_0$ )

e. g. by defining a cut value  $t_{cut}$  :

$t < t_{cut}$  “accepted”

$t > t_{cut}$  “rejected”



Selecting  $t_{cut}$  (decision boundary), one defines significance level of the test:

$$\alpha = \int_{t_{cut}}^{\infty} g(t|H_0) dt$$

meaning that there is the probability  $\alpha$  to reject the hypothesis  $H_0$ , if  $H_0$  is true – called an “error of the first kind”

Probability to accept  $H_0$  if an alternative hypothesis  $H_1$  is true is given by :

$$\beta = \int_{-\infty}^{t_{cut}} g(t|H_1) dt$$

= “error of the second kind”

$1 - \beta$  is called the power of the test to discriminate against the alternative hypothesis  $H_1$

Example 1: Particle identification

test statistic = measured specific energy loss (for fixed momentum)

e. g.  $H_0 = e$ ;  $H_1 = \pi$

Assumption: Only electrons and pions are in sample

Task: Select a sample of electrons (“signal”) by requiring  $t < t_{cut}$

Selected pions are background. Probabilities to select electrons and pions (“efficiencies”) are :

$$\varepsilon_e = \int_{-\infty}^{t_{cut}} g(t|e) dt = 1 - \alpha \qquad \varepsilon_\pi = \int_{-\infty}^{t_{cut}} g(t|\pi) dt = \beta$$

How to choose  $t_{cut}$ ?

large  $t_{cut}$ : large signal efficiency, much background

small  $t_{cut}$ : small signal efficiency, little background (= large purity)

Number of accepted particles:

$$N_{acc} = \varepsilon_e N_e + \varepsilon_\pi N_\pi = \varepsilon_e N_e + \varepsilon_\pi (N_{tot} - N_e)$$

$$\Rightarrow N_e = \frac{N_{acc} - \varepsilon_\pi N_{tot}}{\varepsilon_e - \varepsilon_\pi} \quad (\text{can only be used if } \varepsilon_e \neq \varepsilon_\pi)$$

Probability that a particle with observed value of test statistic  $t$  is an electron:

$$h(e|t) = \frac{a_e g(t|e)}{a_e g(t|e) + a_\pi g(t|\pi)}$$

$a_e, a_\pi = 1 - a_e$  are prior probabilities for electrons and pions, respectively

→ must be known (for example from MC simulation)

Purity :

$$p_e = \frac{N_{\text{electrons with } t < t_{\text{cut}}}}{N_{\text{all part. with } t < t_{\text{cut}}}} = \frac{\int_{-\infty}^{t_{\text{cut}}} a_e g(t|e) dt}{\int_{-\infty}^{t_{\text{cut}}} a_e g(t|e) dt + \int_{-\infty}^{t_{\text{cut}}} (1 - a_e) g(t|\pi) dt} = \frac{a_e \varepsilon_e N_{tot}}{N_{acc}}$$

Example 2: Counting experiment

An experiment counts events of a certain type. Events comprise (on average)  $\nu_B$  background and  $\nu_S$  signal events

The observed number of events is  $n$

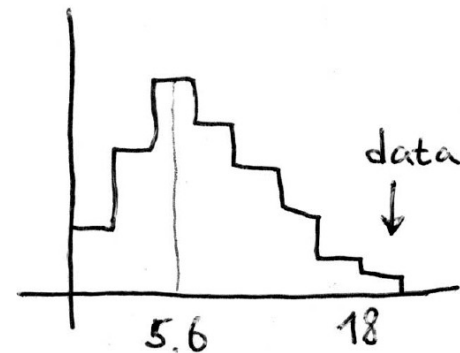
Test statistic: Poisson probability

$$f(n; \nu_S, \nu_B) = \frac{(\nu_S + \nu_B)^n}{n!} e^{-(\nu_S + \nu_B)}$$

null hypothesis :  $f(n|H_0) = f(n; 0, \nu_B)$

Example:  $\nu_B = 5.6$  ,  $n = 18$

Question: Probability to observe 18 or more events if one expects on average 5.6 and  $H_0$  is true



$$p\text{-value}(CL_B) = \sum_{n=n_{data}}^{\infty} f(n; 0, \nu_B) = 1 - \sum_{n=0}^{n_{data}-1} f(n; 0, \nu_B) = 2.4 \cdot 10^{-5}$$

p-value is often expressed in terms of equivalent (Gaussian) std. deviations

$$P(1\sigma) = 1 - \int_{-1}^1 \frac{1}{\sqrt{2\pi}} e^{-\frac{x^2}{2}} dx = 0.3173$$

$$P(2\sigma) = 1 - \int_{-2}^2 \frac{1}{\sqrt{2\pi}} e^{-\frac{x^2}{2}} dx = 0.0455$$

$$P(3\sigma) = \dots = 2.7 \cdot 10^{-3}$$

$$P(4\sigma) = \dots = 6.3 \cdot 10^{-5}$$

$$P(5\sigma) = \dots = 5.7 \cdot 10^{-7}$$

Convention: if p-value ( $CL_B$ ) < “ $5\sigma$ ” ( $5.7 \cdot 10^{-7}$ ), then the background hypothesis is rejected (“discovery”)

Note:

- That does not mean that one detects a signal with  $1-p=0.99\dots$   
(no statement is made about  $H_1$ )
- Requires exact understanding of expected background

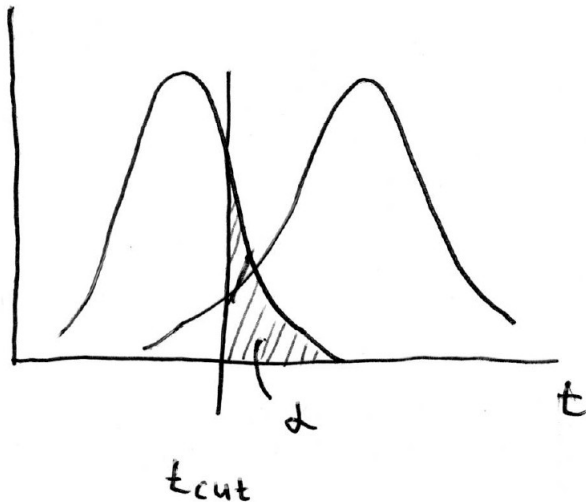
### Choice of the critical region

How does one choose a critical region of a statistical test in an optimal way?

If one defines a significance level  $\alpha$  for a null hypothesis, one wants the largest possible power  $1 - \beta$ .

In other words: For a fixed efficiency  $\varepsilon = 1 - \alpha$ , we want the largest possible purity

For a one dimensional test statistic:

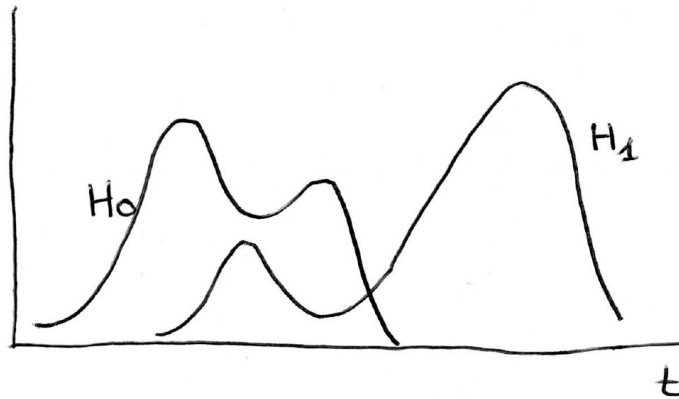


trivial, if  $\frac{\rho(t|H_0)}{\rho(t|H_1)}$  is monotonic function

In that case the value of  $t_{cut}$  fixes  $1 - \beta$

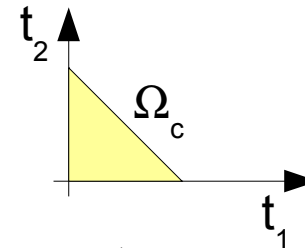
More difficult:

a) more complicated p.d.f. of test statistic



a simple cut might not be optimal

b) multidimensional test statistic



$$\frac{1-\beta}{\alpha} = \frac{\int_{\Omega_c} g(\vec{t}|H_1) d\vec{t}}{\int_{\Omega_c} g(\vec{t}|H_0) d\vec{t}} = \frac{\int_{\Omega_c} \frac{g(\vec{t}|H_1) d\vec{t}}{g(\vec{t}|H_0) d\vec{t}} g(\vec{t}|H_0) d\vec{t}}{\int_{\Omega_c} g(\vec{t}|H_0) d\vec{t}} = E\left(\frac{g(\vec{t}|H_1)}{g(\vec{t}|H_0)}\right)_{|\Omega_c}$$

→  $1 - \beta$  will be maximal, if one selects the region  $\Omega_c$  such that the ratio  $\frac{g(\vec{t}|H_1)}{g(\vec{t}|H_0)}$  is maximised.

Equivalently: Select acceptance region  $1 - \Omega_c$  such that  $\frac{g(\vec{t}|H_0)}{g(\vec{t}|H_1)}$  is minimal

### Neyman-Pearson lemma:

The acceptance region giving the highest power (and signal purity) for a given significance level  $\alpha$  (or selection efficiency  $\varepsilon = 1 - \alpha$ ) is the region in t-space such that:

$$\frac{g(\vec{t}|H_0)}{g(\vec{t}|H_1)} > t_c$$

where  $t_c$  is determined by the desired efficiency

The quantity  $r = \frac{g(\vec{t}|H_0)}{g(\vec{t}|H_1)}$

is called likelihood ratio

→ reduction of n-dimensional test statistic  $\vec{t}$  to one-dim. statistic  $r$

Important property of LR:

n independent measurements with test statistics  $t_1, \dots, t_n$ :

$$g(\vec{t}|H_0) = g_1(t_1|H_0) \dots g_n(t_n|H_0)$$

and

$$g(\vec{t}|H_1) = g_1(t_1|H_1) \dots g_n(t_n|H_1)$$

$$\rightarrow r = \frac{g(\vec{t}|H_0)}{g(\vec{t}|H_1)} = \frac{g_1(t_1|H_0)}{g_1(t_1|H_1)} \dots \frac{g_n(t_n|H_0)}{g_n(t_n|H_1)} = r_1 \dots r_n$$

Example: Counting experiment

$$r_i = \frac{g(N_i|s+b)}{g(N_i|b)} = \frac{(s_i+b_i)^{N_i} \exp(-(s_i+b_i))}{\frac{b_i^{N_i}}{N_i!} \exp(-b_i)}$$

$$= \left( \frac{s_i+b_i}{b_i} \right)^{N_i} \exp(-s_i)$$

Combination of many counting experiments with different purities:

$$r_{tot} = \exp(-s_{tot}) \prod_{i=1}^n \left( \frac{s_i + b_i}{b_i} \right)^{N_i} \quad (s_{tot} = \sum s_i)$$

or

$$\log r_{tot} = -s_{tot} + \sum_{i=1}^n N_i \log \left( 1 + \frac{s_i}{b_i} \right)$$

= weighted sum of events